



Atomic Force Microscopy Related Techniques -application to Tribology, Colour Imaging and Artificial Reproduction Technology

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Meeting link: https://bit.ly/3lV4kAE (MS Teams)

ABSTRACT

Abstract Atomic Force Microscopy (AFM) relies on detection of force at the atomic level for imaging with extremely high resolution. Due to this operating principle, the microscope offers a wide range of application in field of mechanical sensing in the sub-micron regime. I would like to introduce the application of the detection scheme to positioning, Tribology, multi-degrees of freedom force control, and colour imaging. I would also like to share preliminary results on « listening » to gametes or reproduction cells for future applications in artificial reproduction technology.



Session chair: Prof. M. S. Bobji, mecheng@IISc